

CALIBRATION OF  
AC-DC CURRENT TRANSFER STANDARDS  
BASED ON  
CALCULABLE THERMAL CONVERTERS ON  
QUARTZ SUBSTRATE

Torsten Funck



- **Introduction**
- **Quartz-PMJTCs for current transfer**
- **Calculation of the current transfer difference**
- **Validation of the model used for calculation**
- **Measurement setup**
- **AC-DC current transfer standards**
- **Step-up chains**
- **Improved measurement uncertainties**
- **Conclusions**



Electrical quantities are defined, realized and maintained at direct current (dc).

For alternating current (ac) calibrations, traceability is given due to ac-dc transfer.

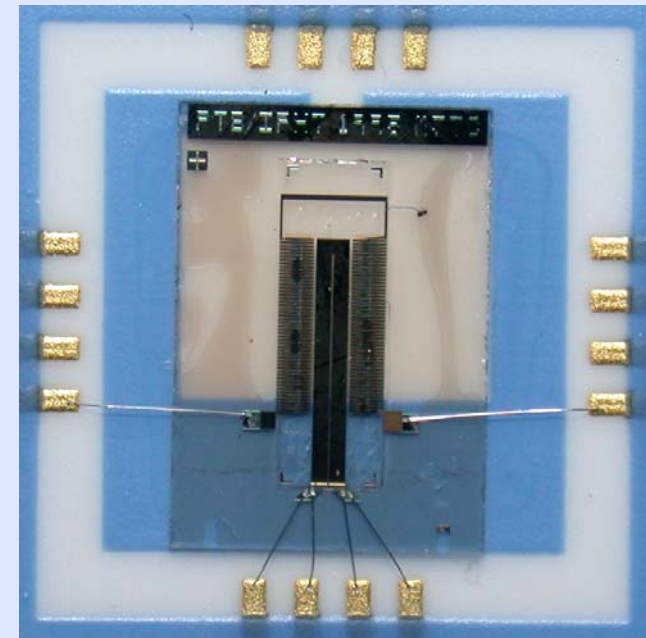
For current, the measured quantity is  $\delta_i$ , the ac-dc current transfer difference:

$$\delta_1 = \frac{I_{ac} - I_{dc}}{I_{dc}}$$

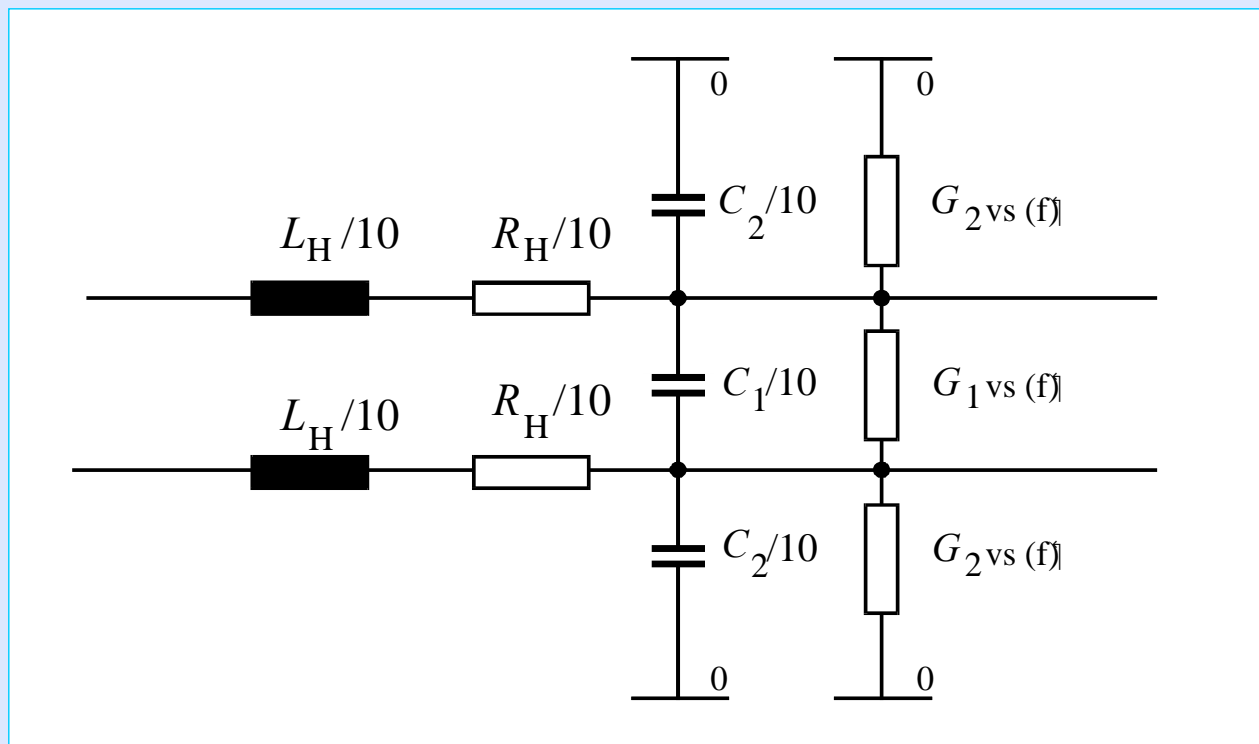


**P**lanar **m**ultijunction **t**hermal **c**onverters (PMJTCs) on a quartz substrate are used as a calculable standard

- + Very low conductivity of the substrate
- + Low dielectric constant  $\epsilon_r$
- + Low, calculable transfer difference
- Difficult to manufacture
- Low thermal time-constant
- Low sensitivity



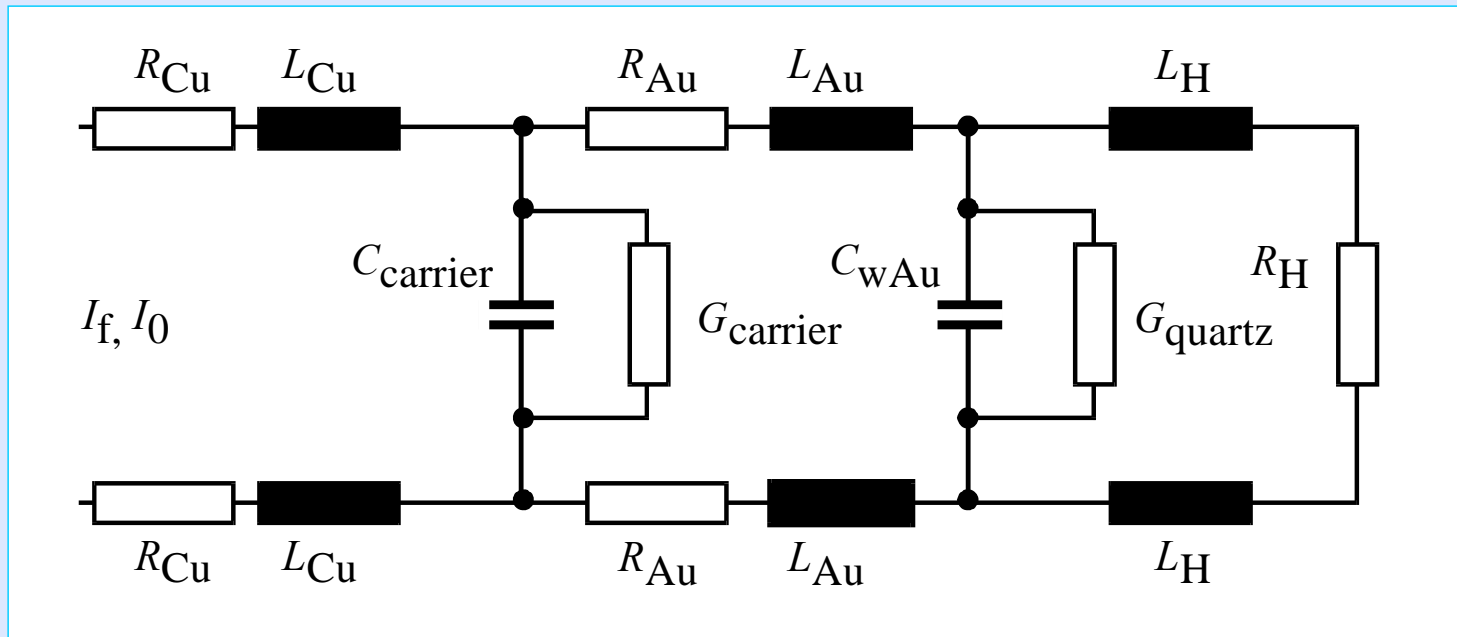
# Calculation of $\delta_i$ due to heater impedance



$$\delta_{i1} = \sqrt{\frac{R_H}{\text{Re}\{Z\}}} - 1$$

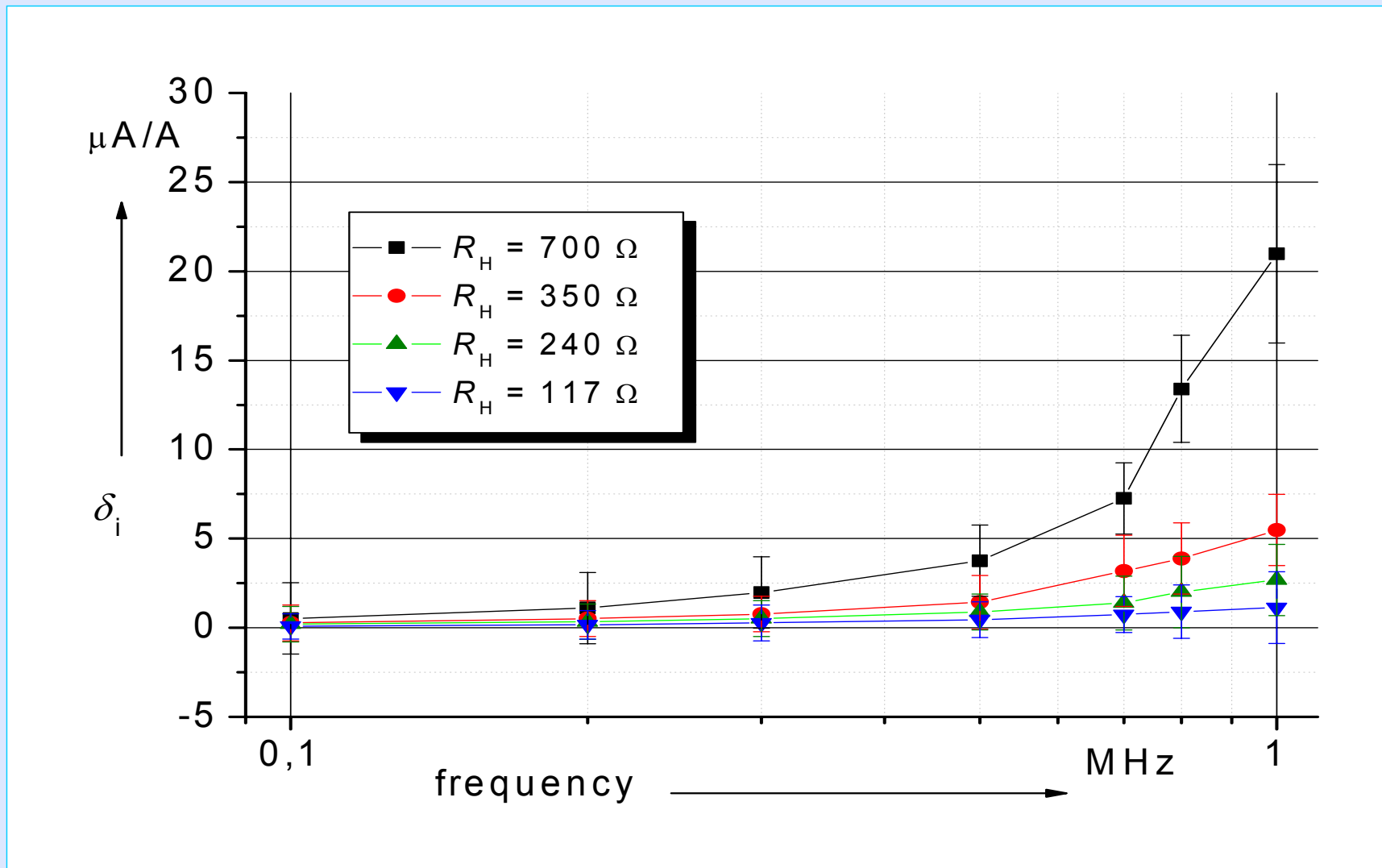


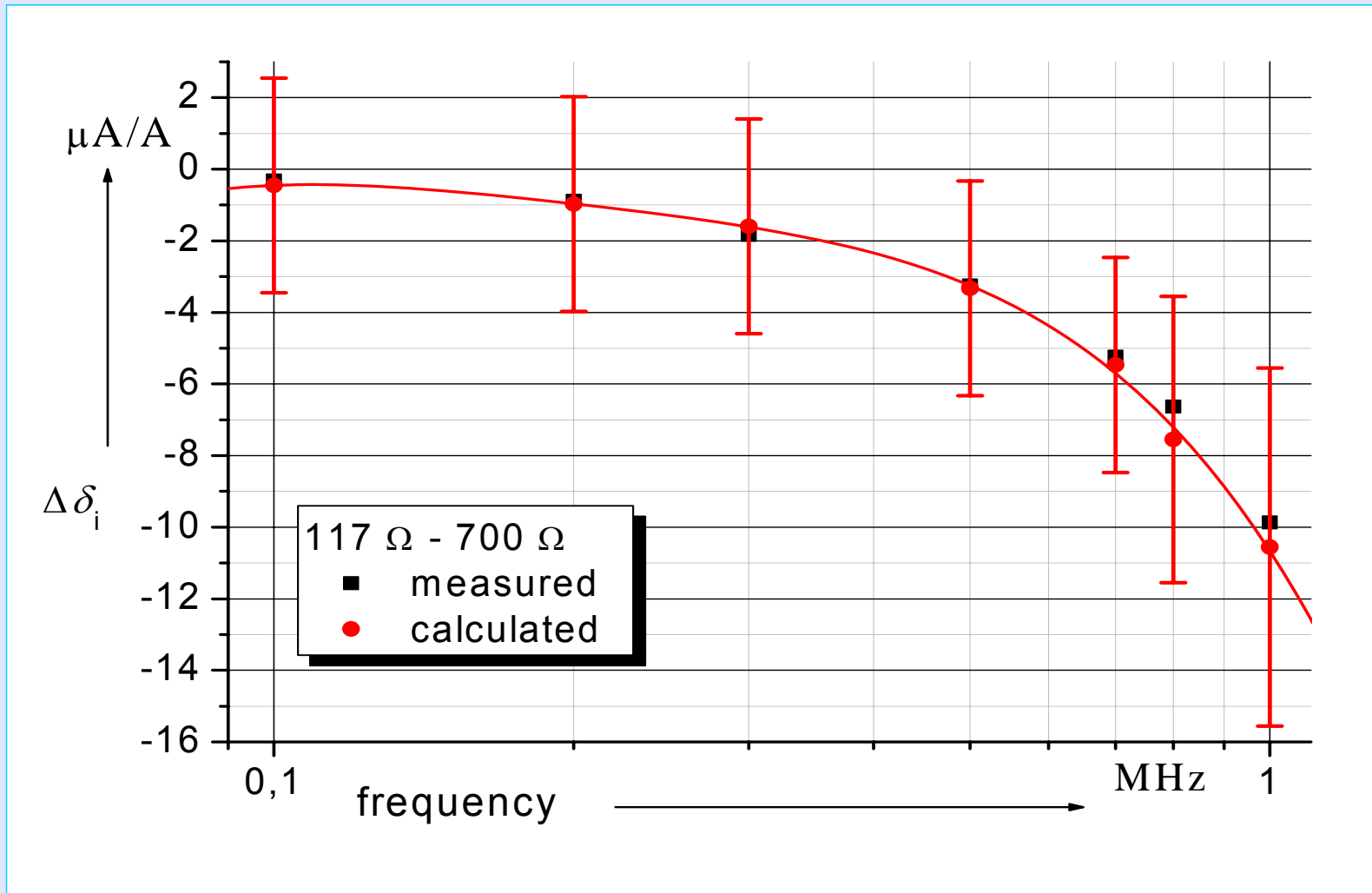
# Calculation of $\delta_i$ due to stray capacitances



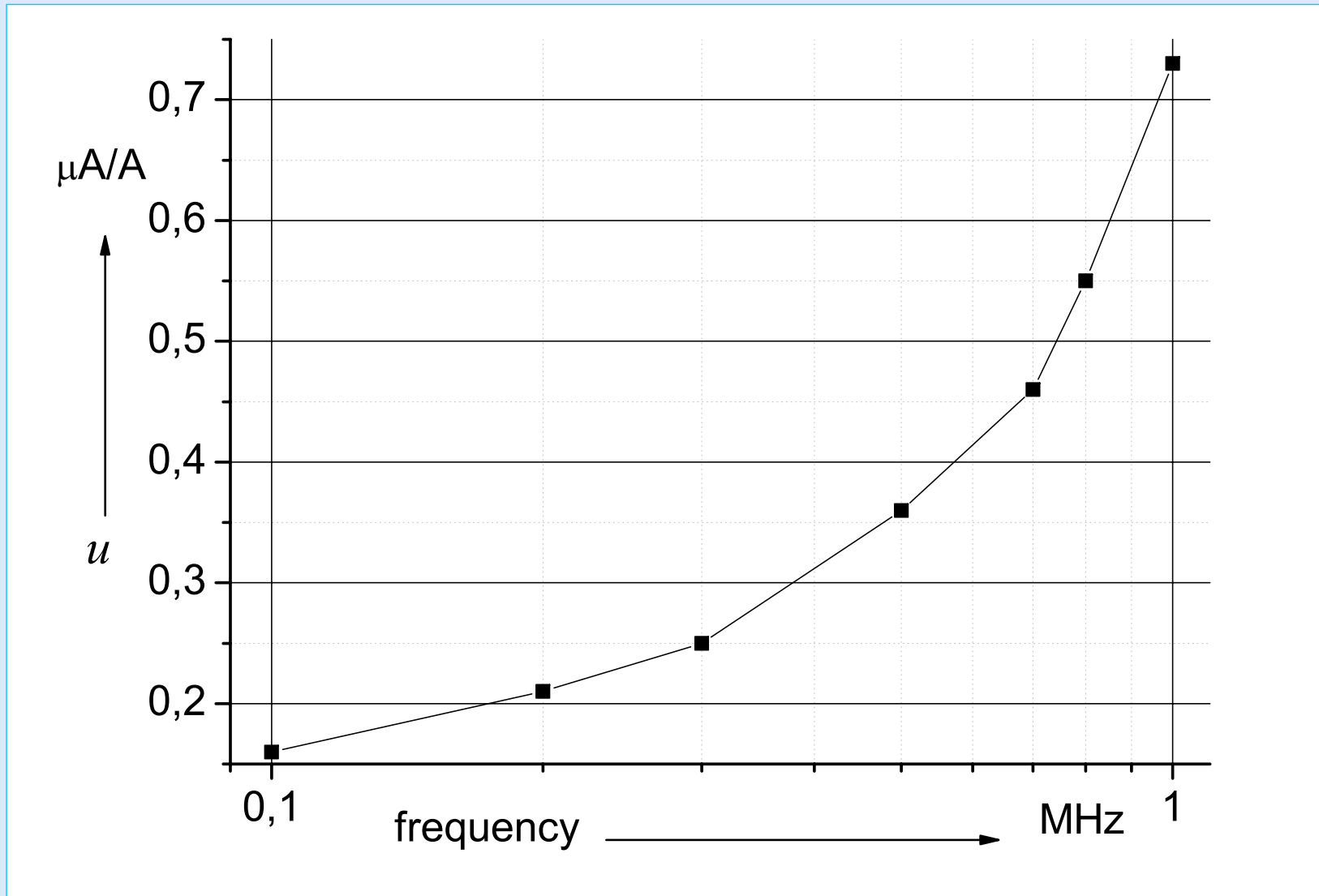
$$\delta_{12} = \frac{\left| \underline{Z}_2 \cdot (\underline{Z}_3 + \underline{Z}_4) \right|}{\left| \underline{Z}_3 \cdot (2 \cdot \underline{Z}_1 + \underline{Z}_2) \right|} - 1$$

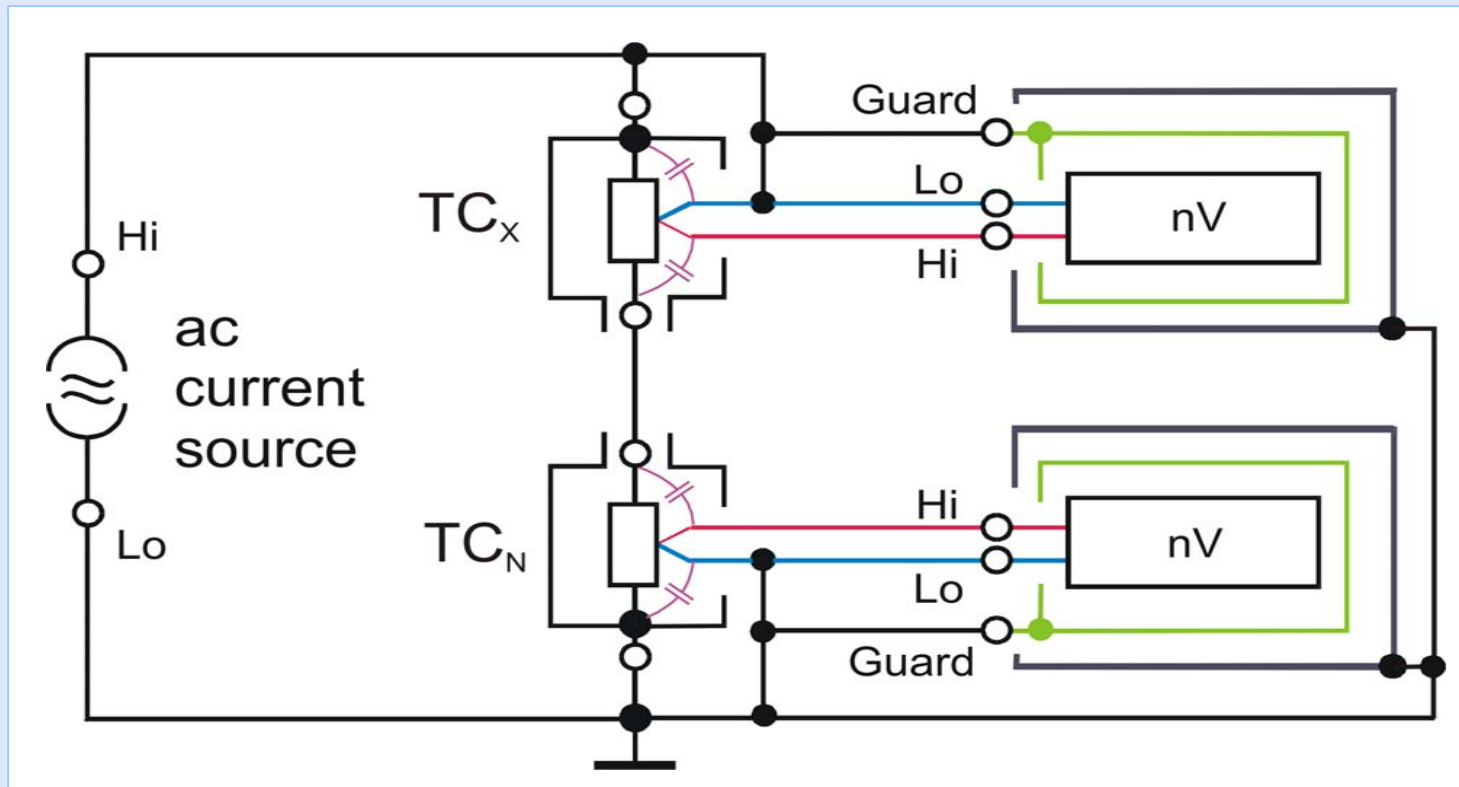












- Symmetrical setup
- Upper standard connected „upside down“
- Constant voltage across parasitic capacitances => equal transfer differences in “upper position” and “lower position”

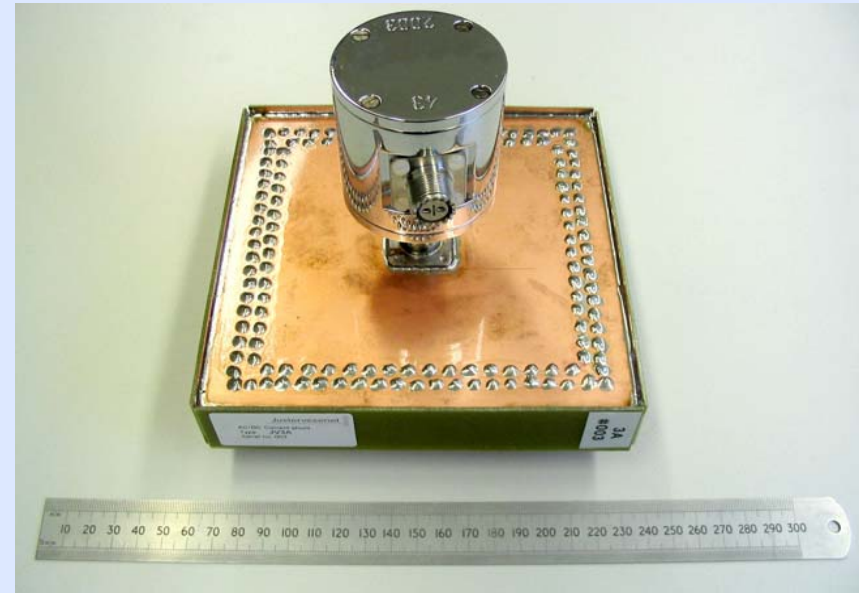
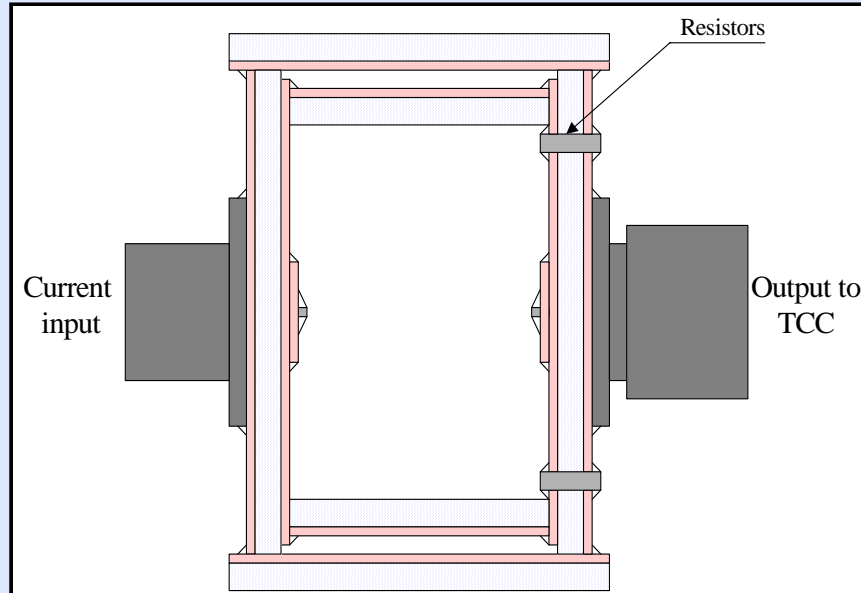
- **Low currents:** **PMJTC with low heater resistance**  
**Problem:** **Technology limits  $90 \Omega < R_H < 900 \Omega$**
- **Medium currents:** **Shunt + PMJTC**  
**Problems:** **Shunt inductance**  
**Current dependence**
- **High currents:** **Cooled shunt + PMJTC**  
**Problems:** **Shunt inductance**  
**Current dependence**  
**Compliance voltage of current source**





- Up to 300 mA: PTB design (top)
- 500 mA to 5 A: Holt design (middle)
- 10 A and 20 A: Fluke design (bottom)





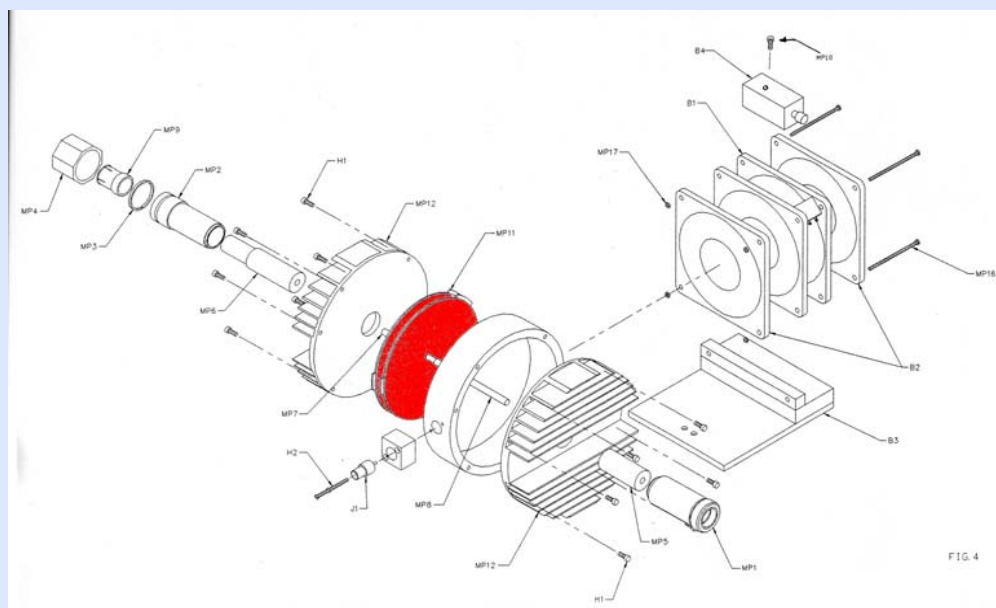
- + Low cost materials
- + Large number of resistors ensure equal current distribution
- + Very small area of current path yields low inductive coupling
- No case



Justervesenet



## High current shunts



## EL-9800 (NIST Design)

### Set of four shunts:

- 10 A to 30 A (25 mΩ)
- 30 A to 50 A (10 mΩ)
- 50 A to 80 A (5 mΩ)
- 80 A to 100 A (3 mΩ)



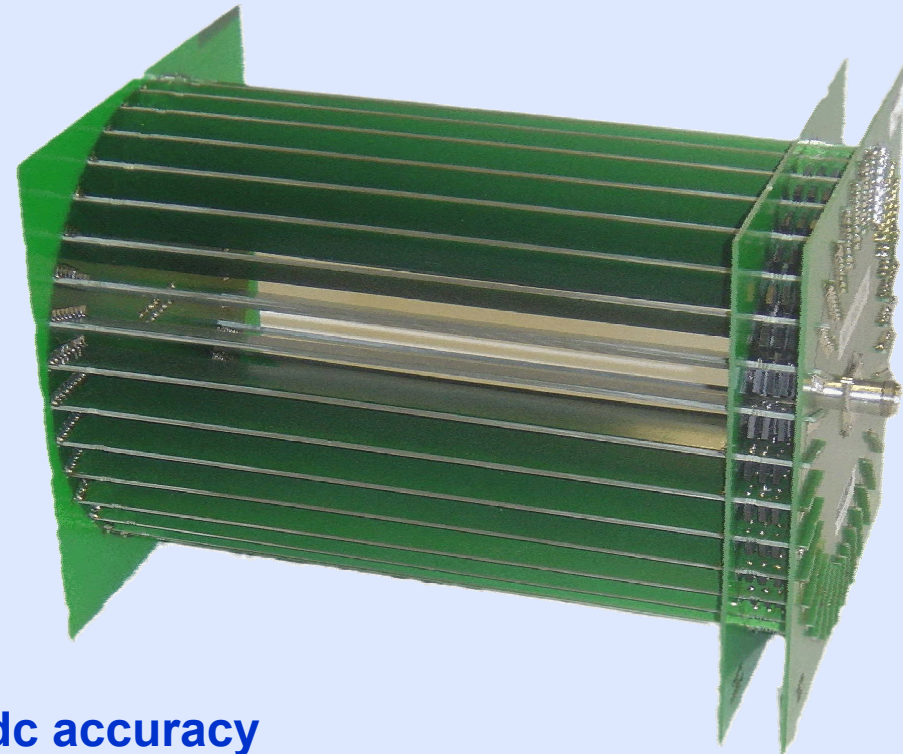


## New high current shunts

Proven design scaled for  
higher currents

800 mV nominal output  
voltage

Available up to 100 A



- + Precision resistors provide also dc accuracy
- + Large number of resistors ensure equal current distribution
- + Small area of current path yields low inductive coupling
- No case
- Quite expensive

## Step-up chains using different standards

Step \ Chain	A	B	C
start	20 mA	30 mA	30 mA
1	50 mA	100 mA	100 mA
2	100 mA	500 mA	300 mA
3	200 mA	1 A	1 A
4	500 mA	5 A	3 A
5	1 A		5 A
6	2 A		
7	5 A		

**Chains A & B: Self-made and Holt shunts**

**Chain C: Justervesenet-Shunts (two sets)**

**Comparison of the chains: 1 A at 1 MHz:  $\Delta < 10 \mu\text{A/A}$**

**5 A at 100 kHz:  $\Delta < 5 \mu\text{A/A}$**





### Assumption:

Current level dependence of shunts  
results from self-heating

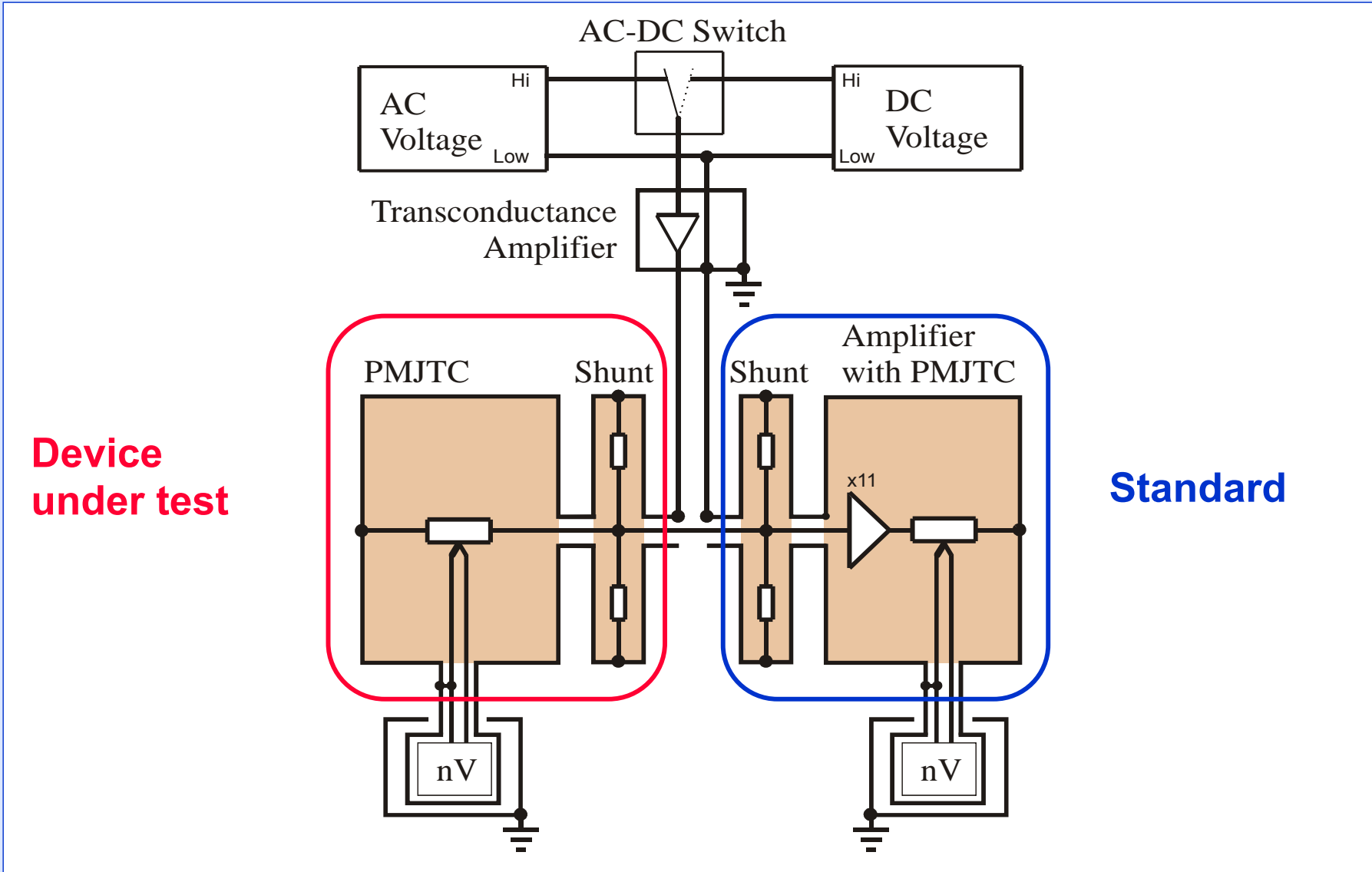
### Measurement approach:

Shunt with low voltage drop used as a standard

- => Low power => low self-heating => low current level dependence
- Low voltage drop => voltage-amplifier necessary to operate PMJTC



# Measurement setup: Shunt with Amplifier



Device under test

Standard



The following sources of uncertainty of the step-up procedure can be identified for each step:

$u(\delta_{\text{std}})$  Standard uncertainty of the (calculable) transfer difference of the standard used, i.e. uncertainty of previous step

$u(\delta_{\text{C}})$  Standard uncertainty of the comparison procedure

$u(\delta_{\text{A}})$  Type A standard uncertainty, i.e. the standard deviation of the mean

$u(\delta_{\text{Lev}})$  Standard uncertainty due to the current level effects in the shunt

$u(\delta_{\text{LF}})$  Standard uncertainty due to PMJTC low frequency effects, which are level dependent



Current	Expanded uncertainty of measurement in $\mu\text{A/A}$ at the frequencies					
	10 Hz	1 kHz	10 kHz	100 kHz	500 kHz	1 MHz
30 mA	5	5	5	10	-	-
	1	1	1	1	1	2
100 mA	5	5	5	10	-	-
	2	2	2	2	2	5
300 mA	10	10	10	20	-	-
	2	2	2	2	3	5
1 A	10	10	10	30	-	-
	4	3	3	4	6	10
3 A	20	20	20	60		
	4	4	4	8		
10 A	25	25	25	80		
	12	12	12	25		
30 A	-	-	-	-		
	30	30	60	120		
100 A	-	-	-	-		
	40	40	80	150		

Red : old (2002)

Blue: (2006)



- **PMJTCs on quartz substrate developed at PTB are well suited for current transfer at low current up to 1 MHz**
- **Potential driven guarding reduces the uncertainty of the comparison measurements**
- **New shunts with low current level dependence and low transfer difference allow further reduction of the step-up procedure's uncertainty**
- **New approaches for the determination of the current level dependence allow for corrections and therefore for further reduction of the uncertainty**



**Thank you for your  
attention!**

**Torsten Funck**

